High-field test at KEK

CLIC Workshop Oct. 16-18, CERN

T. Higo, KEK

Contributors

- Accelerator
 - S. Fukuda
 - S. Matsumoto
 - M. Akemoto
 - M. Yoshida
 - K. Yokoyama
 - N. Kudoh
 - T. Higo

Total FTE = $4 \sim 5$

- KEK MEC staff
 - K. Ueno
 - Y. Higashi
 - T. Takatomi
- Somewhat helped by KEKB injector team
- Operation will be supported by KEKB operators during its operation

High-field test at KEK

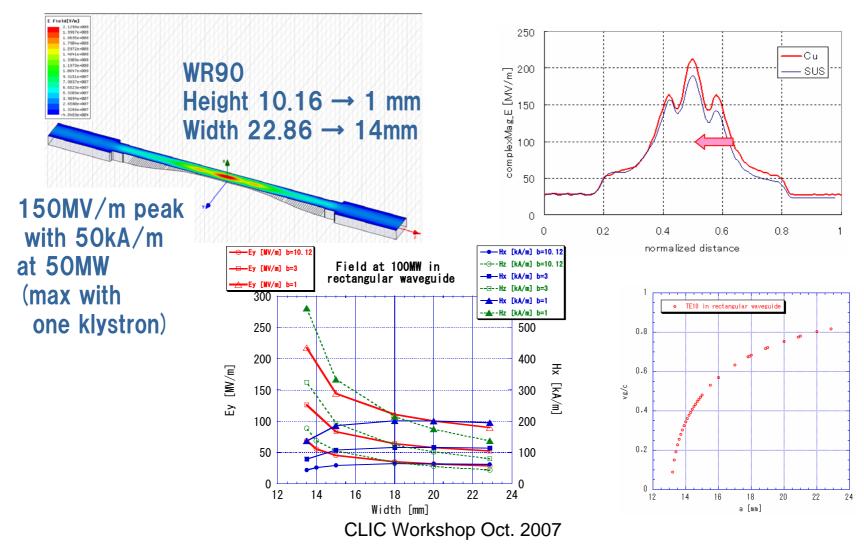
• Klystron assembly hall

- High field test is on-gong with narrow waveguide
 - Cupper and SUS models are tested

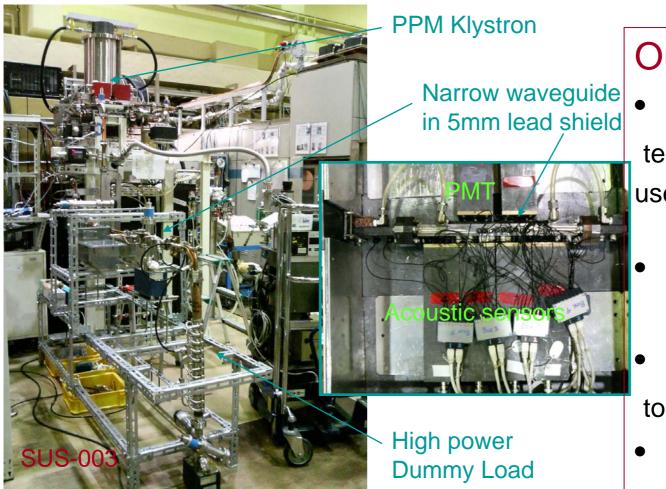
Nextef

- Start-up status
 - Combined power into shield room is foreseen in this month
- Near future plan
 - System establish with old structure
 - Hope to test new CLIC-related structure early next year

Narrow Waveguide Design



Setup for High-Power processing @ klystron assembly hall of Nextef



Our Plan

• Cu-002

tested at XTF and used for startup of new system (May)

• SUS-003

now under test

• Cu-004

to be tested (next)

Other samples

to be tested (future)

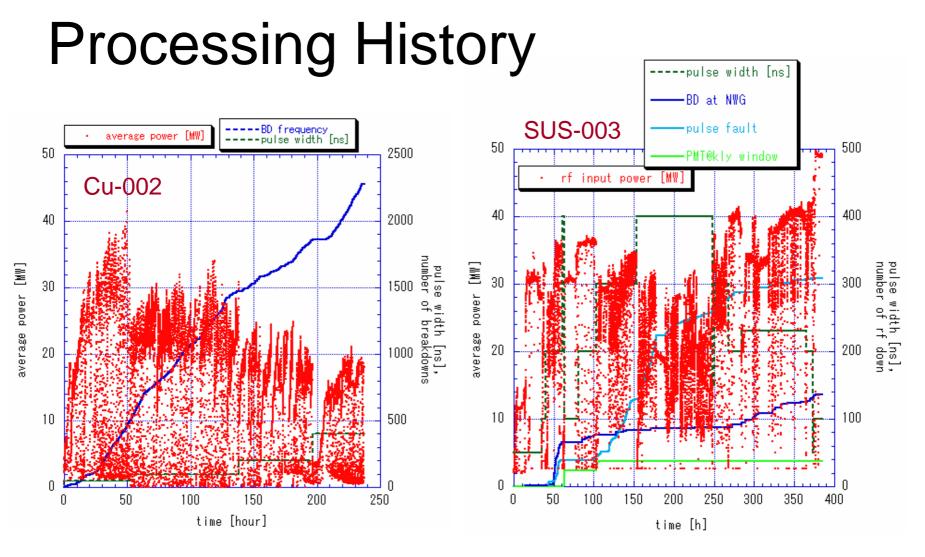
Fabrication



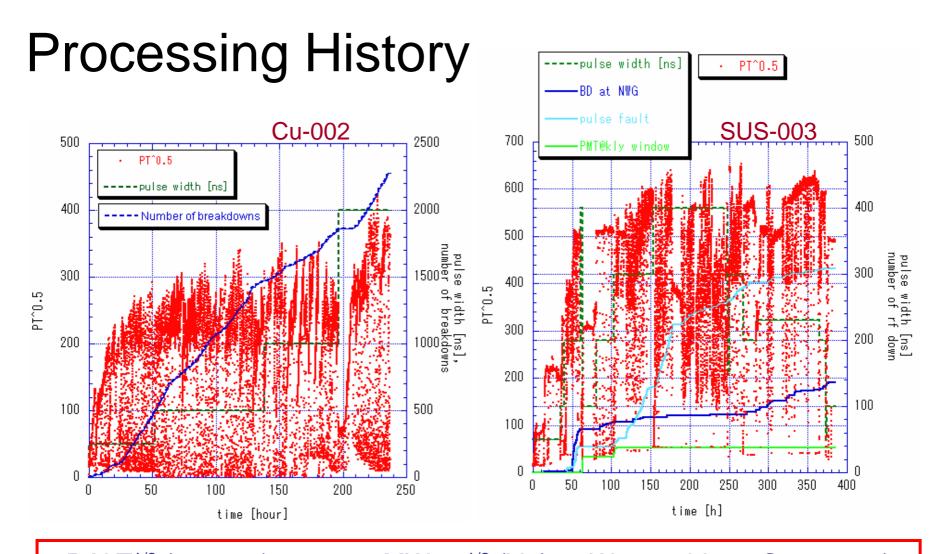
Narrow waveguide consists of 4 parts. These are joined by brazing.

	Cu-002	SUS-003	Cu-004
material	OFC	SUS316L	OFC
annealing	500 °C	1020 °C	500 °C
processes	Milling & WC	milling	milling
cleaning	СР	SUSpika*	СР
bonding	Cu/Au/Ni,	Cu/Au,	Cu/Au
	Brazing (H_2)	Brazing (H ₂)	Brazing (H_2)
VSWR	1.4	1.12	1.02
Test status	finished	Under test	Next

* San-ai plant co. Treatment good for vacuum.



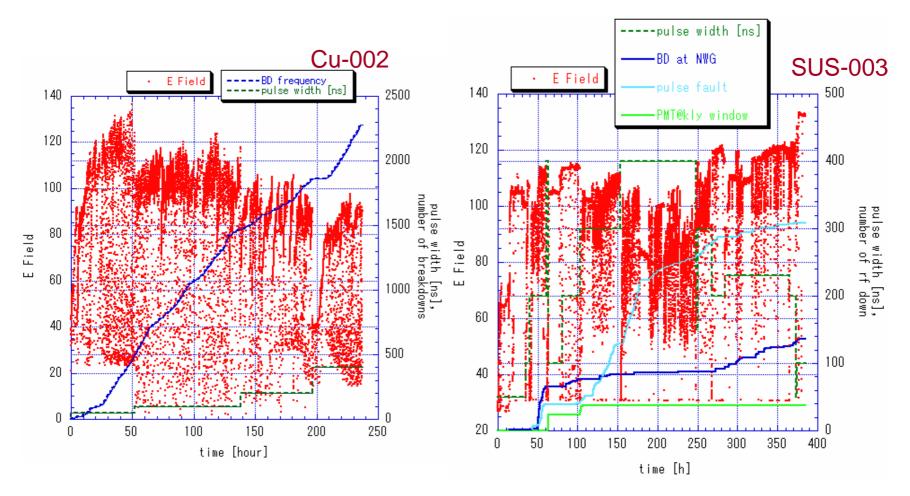
• The RF pulse went from 50 ns to 400 ns feeding up to about 40 MW during processing.



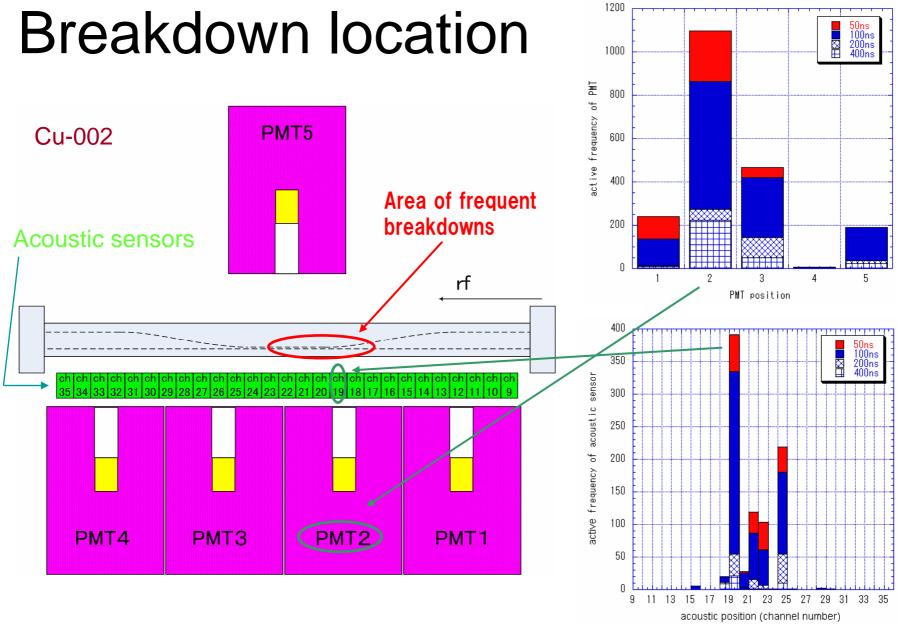
P X T^{1/2} (present) << 2000 MW ns^{1/2} (Valery Waveguide or Structures) Reason? Less-aggressive processing? Less-number of BD?? Surface treatment?

** PT^0.5 means (RF power [MW])* (pulse width Cls)

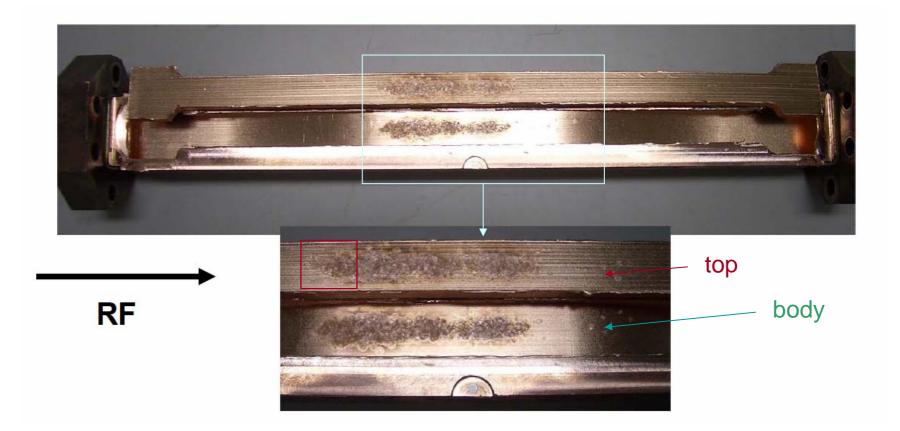
Processing History



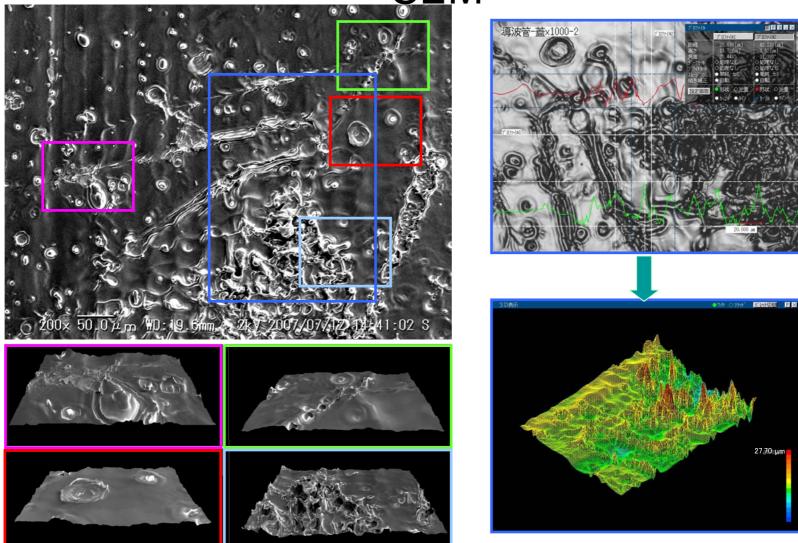
• E Field at the center of narrow waveguide.



Cu-002 After high-power processing



Observation of breakdown surface (top) by <u>SEM</u>



Results Cu-002 \rightarrow SUS-003 \rightarrow Cu-004 \rightarrow

- SUS reached higher PT^{1/2} with smaller number of breakdowns than Cu (tested at GLCTA).
- SUS is limited by guard window. Restarted with TE01 window.
- SUS will be tested in Nextef feeding with two klystrons.
- We will test copper in the present setup again to carefully compare with Cu case.
- Coppers prepared and treated differently will be tested.

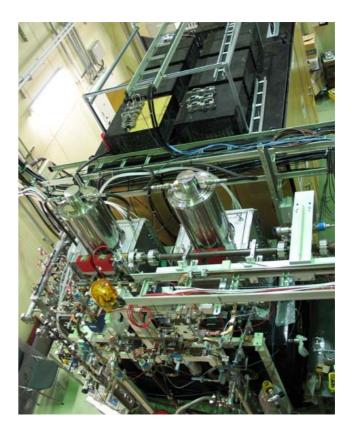
Trial to get good surface for high field

- Y. Higashi has been pursuing various trials
 - Bakeout and installed without exposure to gas
 - Apply SCC technologies such as
 - High-pressure pure-water rinsing
 - Megasonic rinsing
 - Steal various technologies for Si wafer cleaning
- We want to continue and extend these activities
 - With SLAC high gradient test, SW with a few cells
 - With utilizing KEK facility
 - Narrow waveguide or MC+ small-number of cells

Nextef

Nextef

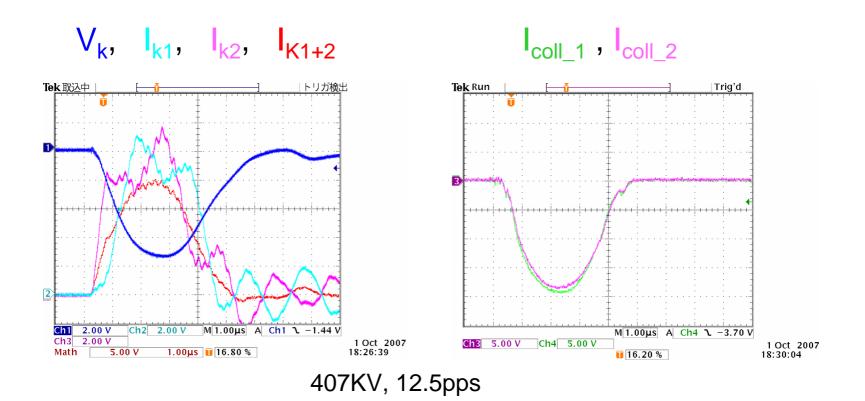




Modulator, klystrons, power transfer line, shield room, control room CLIC Workshop Oct. 2007

Modulator and two klystrons

2-kly operation in high voltage



Two klystrons are driven with a single pulse transformer: Our first experience. It functions well but we suffer from troubles of inverter power supply and thyratron power supply, etc.

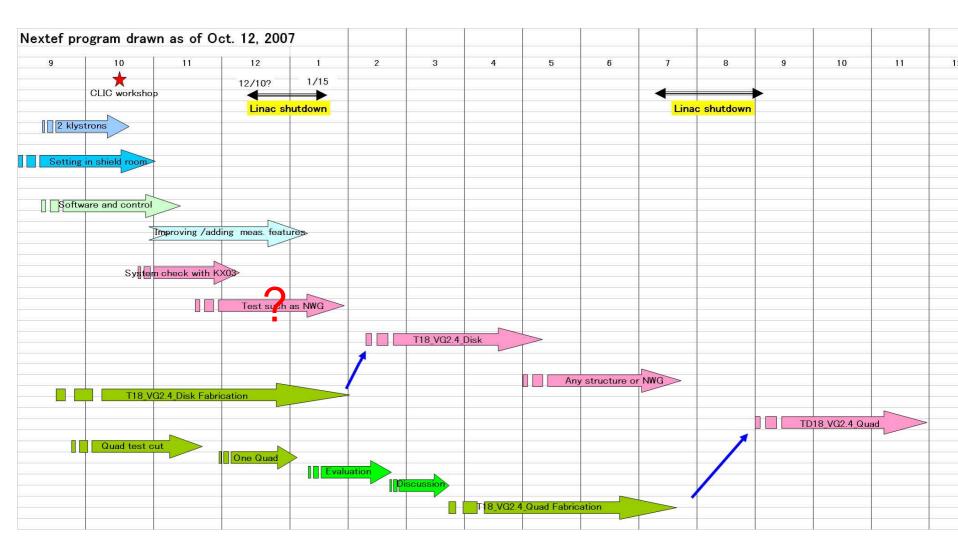
Preparation inside shield room





Girder for structure and beamline components Waveguide and guard window

Nextef planning



Conclusion

- We continue narrow waveguide high-field study for a moment with varying material or surface treatment.
- Nextef will be system checked in November. A series of tests of CLIC-directed structures will be from early next year.
- We are sure that many stages from material and fabrication to installation and processing should be re-examined and refined to realize such high field as CLIC design. We want to proceed the road with you all.